

Search Notes

Application/Control No.

10/524,384

Examiner

Christopher P. Schwartz

Applicant(s)/Patent under
Reexamination

BAYER ET AL.

Art Unit

3683

SEARCHED

Class	Subclass	Date	Examiner
188	1.11E	12/3/2007	CPS
	1.11L		
	71.9		
	72.7		
	72.8		
	158		
	162		
338	2		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST		